

ORDERING INFORMATION

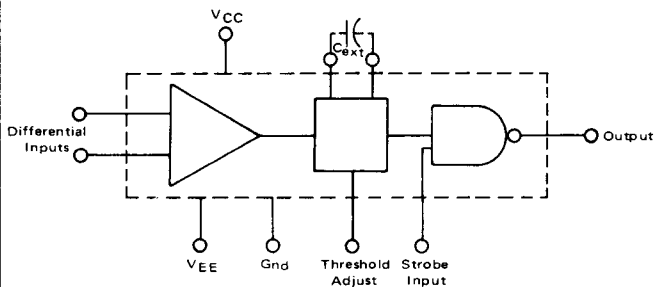
Device	Temperature Range	Package
MC1440G	0°C to +75°C	Metal Can
MC1440L	0°C to +75°C	Ceramic DIP
MC1540G	-55°C to +125°C	Metal Can
MC1540L	-55°C to +125°C	Ceramic DIP

SENSE AMPLIFIER

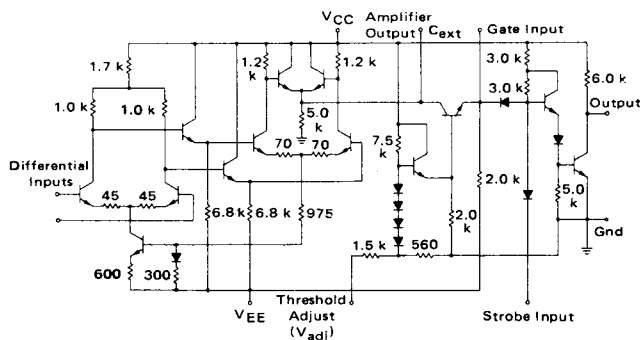
... consisting of a wideband differential amplifier, a dc restoration circuit which also incorporates facilities to externally adjust the threshold, and an MDTL output gate which is strobed from saturated logic. It is designed to detect bipolar differential signals derived by a core memory with cycle times as low as 0.5 μ s.

- Differential Threshold Characteristics:
 - Adjustable Threshold — 10-25 mV
 - Nominal Threshold — 17 mV @ $V_{adj} = 6.0$ V
 - Input Offset Voltage — 1.0 mV typical
 - Threshold Drift — -10 μ V/°C typical
- Fast Response Time — 20 ns typical
- Short Recovery Time :
 - 50 ns max @ $V_i = 1.8$ V Common Mode
 - 50 ns max @ $V_o = 400$ mV Differential Mode

MC1540/MC1440 BLOCK DIAGRAM



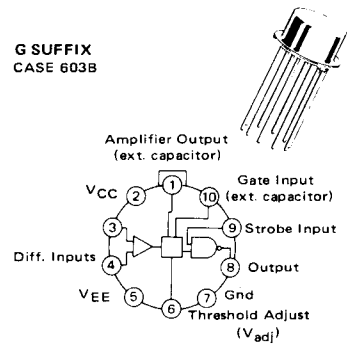
REPRESENTATIVE CIRCUIT SCHEMATIC



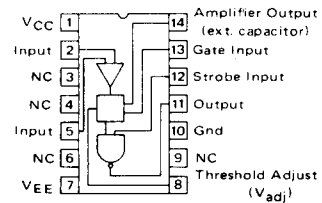
MC1440 MC1540

CORE MEMORY SENSE AMPLIFIER SILICON MONOLITHIC INTEGRATED CIRCUIT

G SUFFIX
CASE 603B



L SUFFIX
CERAMIC PACKAGE
CASE 632
TO-116



MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ unless otherwise noted.)

Rating	Symbol	Value	Unit
Power Supply Voltages	V _{CC}	+10	Vdc
	V _{EE}	-10	Vdc
Differential Input Voltage Range	V _{IDR}	±5.0	Vdc
Common-Mode Input Voltage Range	V _{ICR}	±5.0	Vdc
Output Load Current	I _L	25	mA
Power Dissipation (Package Limitation)	P _D	680	mW
		Metal Can	
		4.6	mW/°C
		Derate above 25°C	
		Flat Package	
		500	mW
		3.3	mW/°C
		Derate above 25°C	
		625	mW
		5.0	mW/°C
		Derate above 25°C	
Operating Ambient Temperature Range	T _A	0 to 75	°C
		-55 to 125	°C
Storage Temperature Range	T _{stg}	-65 to 150	°C

ELECTRICAL CHARACTERISTICS (Unless otherwise noted, $T_A = 25^\circ\text{C}$, $V_{CC} = +6.0\text{ Vdc} \pm 1.0\%$, $V_{EE} = -6.0\text{ Vdc} \pm 1\%$ and $C_{ext} = 0.01\ \mu\text{F}$)

Characteristic	Symbol	MC1540			MC1440			Unit
		Min	Typ	Max	Min	Typ	Max	
Input Threshold Voltage (V _{adj} = -6.0 V, T _A = 25°C) (V _{adj} = -6.0 V, T _A = T _{low} *) (V _{adj} = -6.0 V, T _A = T _{high} *)	V _{th}	14	17	20	12	17	24	mV
		12	17	24	10	17	30	
		12	17	22	10	17	30	
Input Offset Voltage	V _{IO}	-	1.0	5.0	-	1.0	6.0	mV
Input Bias Current (T _A = 25°C) (T _A = T _{high} to T _{low})	I _{IB}	-	7.5	50	-	7.5	75	μA
		-	-	100	-	-	100	
Input Offset Current	I _{IO}	-	2.0	10	-	2.0	15	μA
Output Voltage – High Logic State	V _{OH}	5.9	-	-	5.8	-	-	Vdc
Output Voltage – Low Logic State (I _{OL} = 6.0 mA, V _{IH(G)} = 6.0 V) (T _A = T _{high})	V _{OL}	-	-	350	-	-	400	mV
		-	-	400	-	-	450	
Amplifier Voltage Gain (V _i = 15 mV peak)	A _v	-	85	-	-	85	-	V/V
Strobe Input Current – Low Logic State (V _{IL(S)} = 0 V)	I _{IL(S)}	-	-	1.2	-	-	1.5	mA
Strobe Input Current – High Logic State (V _{IH(S)} = 5.0 V) (V _{IH(S)} = 6.0 V, T _A = T _{high})	I _{IH(S)}	-	-	2.0	-	-	5.0	μA
		-	-	25	-	-	30	
Power Consumption	P _C	-	120	180	-	120	250	mW

*T_{low} = -55°C for MC1540, 0°C for MC1440
T_{high} = 125°C for MC1540, 75°C for MC1440

SWITCHING CHARACTERISTICS (Unless otherwise noted, $V_{CC} = 6.0\text{ V}$, $V_{EE} = -6.0\text{ V}$, $T_A = 25^\circ\text{C}$, $C_{ext} = 0.01\ \mu\text{F}$.)

Characteristic	Symbol	MC1540			MC1440			Unit
		Min	Typ	Max	Min	Typ	Max	
Propagation Delay Time from Differential Input to Amplifier Output	t _{PLH(A)}	-	10	15	-	10	20	ns
Propagation Delay Time from Differential Input to Low Logic State Output	t _{PHL(A)}	-	20	30	-	20	50	ns
Propagation Delay Time from Strobe Input to Low Logic State Output	t _{PHL(S)}	-	10	15	-	10	30	ns
Differential Mode Recovery Time	t _{R(DM)}	-	20	50	-	20	90	ns
Common-Mode Recovery Time	t _{R(CM)}	-	20	50	-	20	60	ns

FIGURE 1 – THRESHOLD VOLTAGE TEST CIRCUIT AND WAVEFORMS

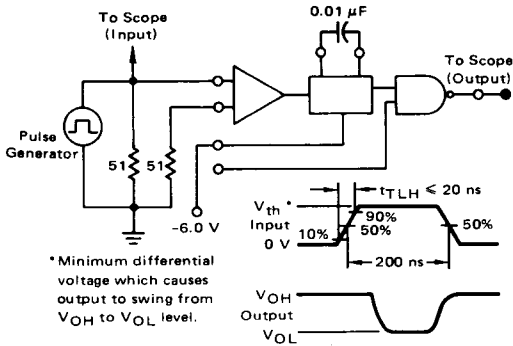


FIGURE 2 – AMPLIFIER VOLTAGE GAIN TEST CIRCUIT AND WAVEFORMS

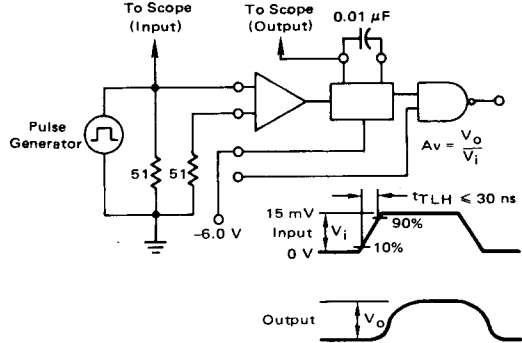


FIGURE 3 – TEST CIRCUIT AND WAVEFORMS FOR PROPAGATION DELAY TIMES FROM DIFFERENTIAL INPUTS TO AMPLIFIER AND GATE OUTPUTS

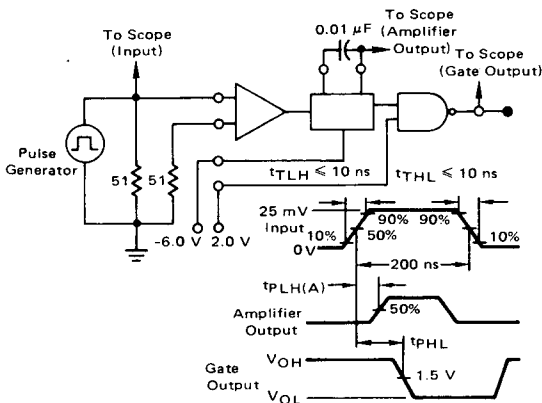


FIGURE 4 – TEST CIRCUIT AND WAVEFORMS FOR PROPAGATION DELAY TIME FROM STROBE INPUT TO OUTPUT

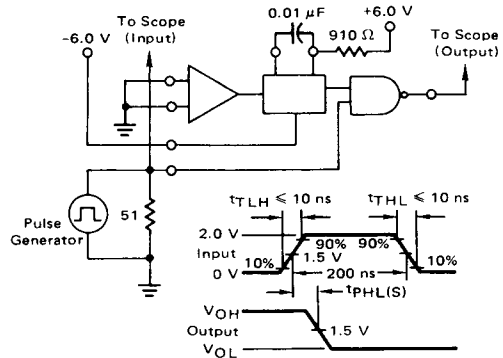


FIGURE 5 – TEST CIRCUIT AND WAVEFORMS FOR DIFFERENTIAL MODE RECOVERY TIME

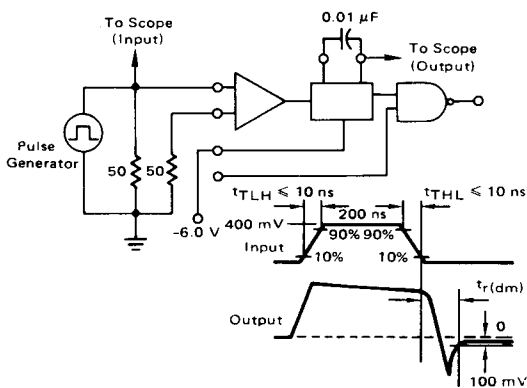
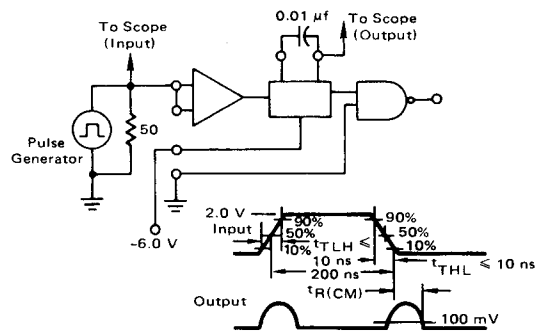


FIGURE 6 – TEST CIRCUIT AND WAVEFORMS FOR COMMON-MODE RECOVERY TIME



NOTE: The output shown is representative of that obtained, however, the two pulse amplitudes may not be equal or even present. Input Pulse width equals 200 ns, $f = 1.0$ MHz.